

<b>Notice of References Cited</b>	Application/Control No. 10/753,524		Applicant(s)/Patent Under Reexamination YAMAZAKI ET AL.	
	Examiner Johannes P. Mondt		Art Unit 2826	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,582,640	12-1996	Okada et al.	117/8
*	B	US-5,854,627	12-1998	Kurihara et al.	345/211
*	C	US-4,810,060	03-1989	Ukai, Yasuhiro	349/43
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08-211367 A	08-1996	Japan	Kurihara et al.	G02F001/133
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Clark, M.G., "Current Status and future prospects of poly-Si devices", in Circuits, Devices and Systems, IEE Proceedings [IEE Proceedings G- Circuits, Devices and Systems], Volume 141, pp. 3-8 (February 1994) (ISSN: 1350-2409) (INSPEC Acc. Nr.: 4631752).
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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